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[Continued on next page]

(54) Title: METHODS AND APPARATUS FOR OPTIMIZATION OF INSPECTION SPEED BY GENERATION OF STAGE SPEED PROFILE AND SELECTION OF CARE AREAS FOR AUTOMATED WAFER INSPECTION

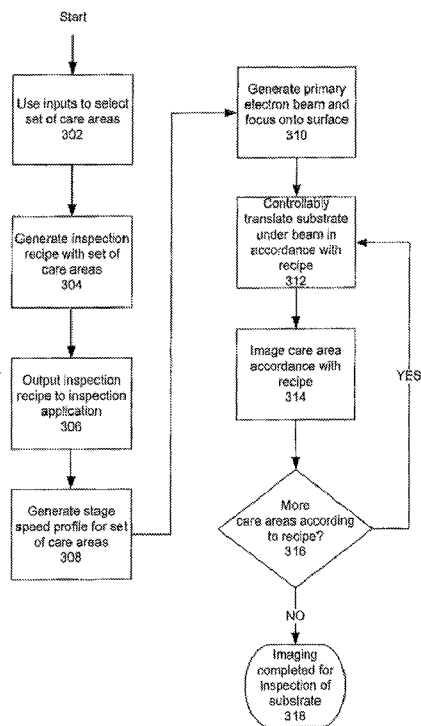


FIG. 3 300

(57) Abstract: Disclosed are apparatus and methods for the generation of a stage speed profile and/or the selection of care areas for automated wafer inspection. The stage speed profile generated corresponds to a fastest speed the inspection machine is able to inspect provided a set of care areas. The set of care areas selected correspond to specific regions on the wafer which are to be imaged in detail by the inspection machine. The apparatus and methods herein may also calculate speed of inspection and coverage (and possibly other characteristics of the inspection) for a quantity of cases, and select the best trade-off of coverage versus inspection time using a cost function. Other aspects, features, and embodiments of the invention are also disclosed.

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SM, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ,
GW, ML, MR, NE, SN, TD, TG).

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B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

H01L 21/66; H01L 21/027; G06F 19/00; G01B 5/28; G06K 9/00; G01N 21/956

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Korean utility models and applications for utility models

Japanese utility models and applications for utility models

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

eKOMPASS(KIPO internal) & Keywords: inspection,beam,scan,speed,optimization,area,profile

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
Y A	US 2003-0063792 A1 (TAKASHI HIROI et al.) 03 April 2003 See abstract; figure 7; paragraphs [0030]-[0031]	1 2-18
Y X A	JP 2009-042055 A (TOSHIBA CORP) 26 February 2009 See abstract; figures 2-5; paragraphs [0023]-[0043]	1 9 2-8, 10-18
A	US 2010-0211202 A1 (CHOU CHIEN-HUNG et al.) 19 August 2010 See figure 2; paragraphs [0030]-[0032]	1-18
A	US 2005-0033528 A1 (TOTH GABOR D. et al.) 10 February 2005 See figure 3; paragraphs [0042]-[0043], [0048]-[0049]	1-18

 Further documents are listed in the continuation of Box C. See patent family annex.

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